

Search Notes

Application/Control No.

10/069,118

Examiner

Shin-Hon Chen

Applicant(s)/Patent under
Reexamination

HATANAKA ET AL.

Art Unit

2131

SEARCHED

Class	Subclass	Date	Examiner
380	201,217, 235-250, 281	8/23/2006	S.C.
713	165-168	8/23/2006	S.C.
705	57	8/23/2006	S.C.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
380	201,217	8/23/2006	S.C.
380	235-250	8/23/2006	S.C.
380	281	8/23/2006	S.C.
713/165-168; 705/57		8/23/2006	S.C.

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPAT, PGPUB, DERWENT, EPO, JPO (BRS search)	8/23/2006	S.C.
Inventor name search on EDAN	8/23/2006	S.C.